Emerging Trends and Approaches to Cyber Security

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Deadline for manuscript submissions:
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Message from the Guest Editors

This special issue focusses on emerging trends and technologies in the broad area of cyber security and include all aspects of the modelling, design, implementation, deployment, and management of security algorithms, protocols, architectures, and system, from physical-layer technology to the application layer.

The topics of interest include, but are not limited to:

* Physical layer security on 5G and beyond 5G technology

* IoT security and privacy

* Resilient IoT framework based on AI/Machine Learning

* Threat detection with AI/ML

* Lightweight cryptographic algorithms for IoT devices

* Biometric and emerging authentication technologies

* Malware detection

* Security and privacy in fog/edge computing

* Security in connected and autonomous vehicles

* Cyber Threat Intelligence

* Secure software development framework

* Social aspects to cyber security

* Cyber crime law

Special Issue

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Message from the Editor-in-Chief

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